Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	•
09/747,004	HU ET AL.	
Examiner	Art Unit	
Young J. Kim	1637	

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Patent Database (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) search updated	2/19/2006	YJK
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